

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TSUCHIYA ET AL.	
		Examiner Sheela C. Chawan	Art Unit 2624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	D	US-6,040,911	03-2000	Nozaki et al.	356/394
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Haruo Yoda et al., "repeating pattern defect detection device", 11/01/1984 United States Patent and Trademark Office, Washington, D.C. March 2007. Pages 1-21.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.